

The PDSP16318 contains two independent 20-bit Adder/Subtractors combined with accumulator registers and shift structures. The four port architecture permits full 10MHz throughput in FFT and filter applications.

Two PDSP16318s combined with a single PDSP16112A Complex Multiplier provide a complete arithmetic solution for a Radix 2 DIT FFT Butterfly. A new complex Butterfly result can be generated every 100ns allowing 1k complex FFT's to be executed in 512 $\mu$ s.

### FEATURES

- Full 10MHz Throughput in FFT Applications
- Four Independent 16-bit I/O Ports
- 20-bit Addition or Accumulation
- Fully Compatible with PDSP16112 Complex Multiplier
- On Chip Shift Structures for Result Scaling
- Overflow Detection
- Independent Three-State Outputs and Clock Enables for 2 Port 10MHz Operation
- 1.4 micron CMOS
- 500mW Maximum Power Dissipation
- 100 pin ceramic QFP

### ORDERING INFORMATION

PDSP16318/MC/GC1R (Ceramic QFP Package - MIL STD 883 Screening)

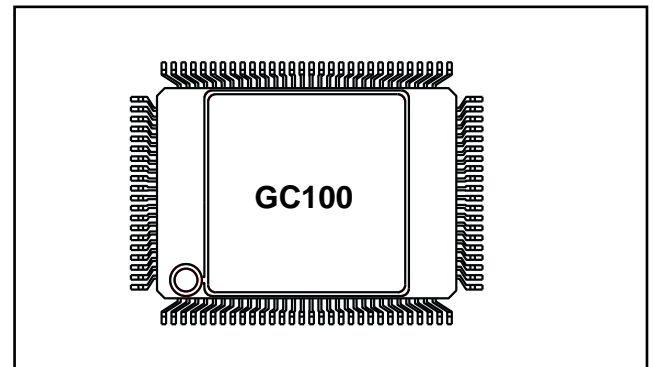


Fig.1 Pin connections

Rev	A	B	C	D
Date	MAR 1993	NOV 1998		

### NOTE

Polyimide is used as an inter-layer dielectric and as glassivation.

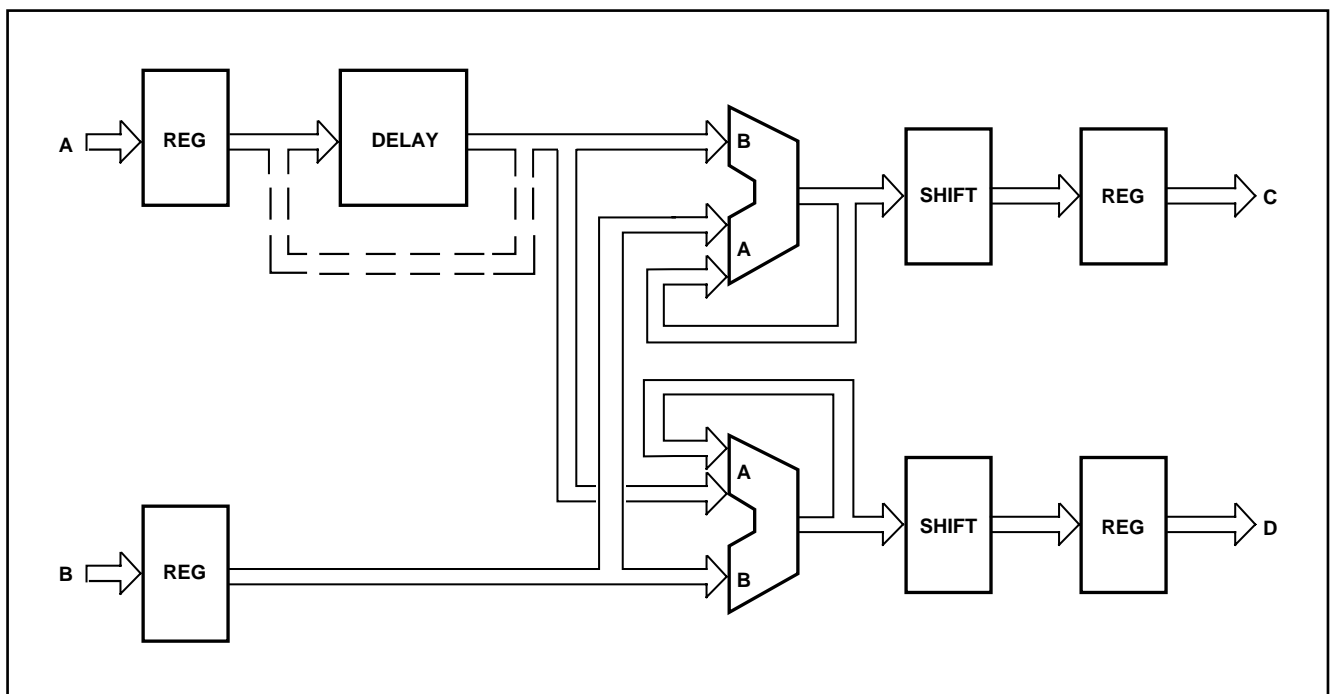


Fig.2 PDSP16318 simplified block diagram

# PDSP16318 MC

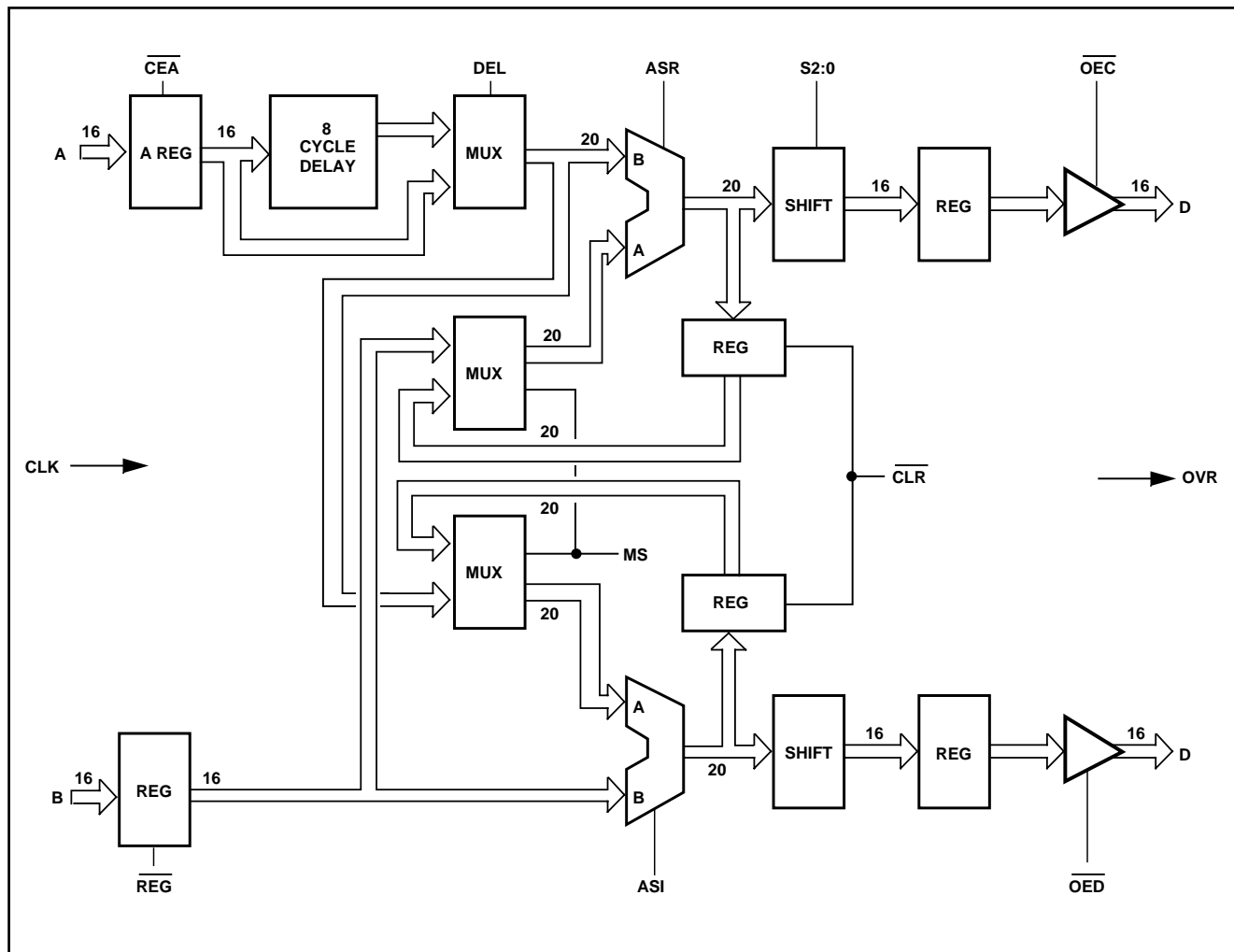


Fig.2 Block diagram

## FUNCTIONAL DESCRIPTION

The PDSP16318 is a Dual 20-bit Adder/Subtractor configured to support Complex Arithmetic. The device may be used with each of the adders allocated to real or imaginary data (e.g. Complex Conjugation), the entire device allocated to Real or Imaginary Data (e.g. Radix 2 Butterflies) or each of the adders configured as accumulators and allocated to real or imaginary data (Complex Filters). Each of these modes ensures that a full 10MHz throughput is maintained through both adders, the first and last mode illustrating true Complex operation, where both real and imaginary data is handled by the single device.

Both Adder/Subtractors may be controlled independently via the ASR and ASI inputs. These controls permit  $A + B$ ,  $A - B$ ,  $B - A$  or pass  $A$  operations, where the  $A$  input to the Adder is derived from the input multiplexer. The CLR control line allows the clearing of both accumulator registers. The two multiplexers may be controlled via the MS inputs, to select either new input data, or fed-back data from

the accumulator registers. The PDSP16318 contains an 8-cycle deskew register selected via the DEL control. This deskew register is used in the FFT applications to ensure correct phasing of data that has not passed through the PDSP16112 Complex Multiplier.

The 16-bit outputs from the PDSP16318 are derived from the 20-bit result generated by the Adders. The three bit S2:0 input selects eight different shifted output formats ranging from the most significant 16 bits of the 20-bit data, to the least significant 13 bits of the 20-bit data. In this mode the 14th, 15th and 16th bits of the output are set to zero. The shift selected is applied to both adder outputs, and determines the function of the OVR flag. The OVR flag becomes active when either of the two adders produces a result that has more significant digits than the MSB of the 16-bit output from the device. In this manner all cases when invalid data appears on the output are flagged.

Symbol	Type	Description
A15:0	Input	<b>Data</b> presented to this input is loaded into the input register on the rising edge of CLK. A15 is the MSB.
B15:0	Input	<b>Data</b> presented to this input is loaded into the input register on the rising edge of CLK. B15 is the MSB and has the same weighting as A15.
C15:0	Output	New <b>data</b> appears on this output after the rising edge of CLK. C15 is the MSB.
D15:0	Output	New <b>data</b> appears on this output after the rising edge of CLK. D15 is the MSB.
CLK	Input	<b>Common Clock</b> to all internal registers
$\overline{\text{CEA}}$	Input	<b>Clock enable:</b> when low the clock to the A input register is enabled.
$\overline{\text{CEB}}$	Input	<b>Clock enable:</b> when low the clock to the B input register is enabled.
$\overline{\text{OEC}}$	Input	<b>Output enable:</b> Asynchronous 3-state output control: The C outputs are in a high impedance state when this input is high.
$\overline{\text{OED}}$	Input	<b>Output enable:</b> Asynchronous 3-state output control: The D outputs are in a high impedance state when this input is high.
OVR	Output	<b>Overflow flag:</b> This flag will go high in any cycle during which either the output data overflows the number range selected or either of the adder results overflow. A new OVR appears after the rising edge of the CLK.
ASR1:0	Input	<b>Add/subtract Real:</b> Control input for the 'Real' adder. This input is latched by the rising edge of clock.
ASI1:0	Input	<b>Add/subtract Imag:</b> Control input for the 'Imag' adder. This input is latched by the rising edge of clock.
$\overline{\text{CLR}}$	Input	<b>Accumulator Clear:</b> Common accumulator clear for both Adder/Subtractor units. This input is latched by the rising edge of CLK.
MS	Input	<b>Mux select:</b> Control input for both adder multiplexers. This input is latched by the rising edge of CLK. When high the feedback path is selected.
S2:0	Input	<b>Scaling control:</b> This input selects the 16-bit field from the 20-bit adder result that is routed to the outputs. This input is latched by the rising edge of CLK.
DEL	Input	<b>Delay Control:</b> This input selects the delayed input to the real adder for operations involving the PDSP16112. This input is latched by the rising edge of CLK.
VCC	Power	<b>+5V supply:</b> Both Vcc pins must be connected.
GND	Ground	<b>0V supply:</b> Both GND pins must be connected.

GG pin	Function	GG pin	Function	GG pin	Function	GG pin	Function
77	D7	6	C7	31	A1	56	B10
82	D8	7	C6	32	A2	57	B9
83	D9	8	C5	33	A3	58	B8
84	D10	9	C4	34	A4	59	B7
85	GND	10	C3	35	A5	60	B6
86	VCC	11	C2	36	A6	61	B5
87	D11	12	C1	37	A7	62	B4
88	D12	13	C0	38	A8	63	B3
89	D13	14	$\overline{\text{OED}}$	39	A9	64	B2
90	D14	15	$\overline{\text{OEC}}$	40	A10	65	B1
91	D15	16	S2	41	A11	66	B0
92	C15	17	S1	42	A12	67	CLK
93	C14	18	S0	43	A13	68	$\overline{\text{CEB}}$
94	C13	19	MS	44	A14	69	OVR
95	C12	20	ASI1	45	A15	70	D0
96	VCC	21	ASI0	46	$\overline{\text{CEA}}$	71	D1
97	GND	22	$\overline{\text{DEL}}$	47	B15	72	D2
98	C11	23	CLR	48	B14	73	D3
99	C10	24	ASR1	49	B13	74	D4
100	C9	25	ASR0	50	B12	75	D5
5	C8	26	A0	51	B11	76	D6

Device Pinout for ceramic QFP (GC100)

# PDSP16318 MC

ASR or ASI		ALU Function
ASX1	ASX0	
0	0	A + B
0	1	A
1	0	A - B
1	1	B - A

DEL	Delay Mux Control
0	A port input
1	Delayed A port input

MS	Real and Imag' Mux Control
0	B port input/Del mux output
1	C accumulator/D accumulator

S2:0			Adder result																				
S2	S1	S0	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0	
0	0	0	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0					
0	0	1			15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0			
0	1	0				15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0		
0	1	1					15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0	
1	0	0						15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
1	0	1							15	14	13	12	11	10	9	8	7	6	5	4	3	2	1
1	1	0								15	14	13	12	11	10	9	8	7	6	5	4	3	2
1	1	1									15	14	13	12	11	10	9	8	7	6	5	4	3

## NOTE

This table shows the portion of the adder result passed to the D15:0 and C15:0 outputs. Where fewer than 16 adder bits are selected the output data is padded with zeros.

## ABSOLUTE MAXIMUM RATINGS (Note 1)

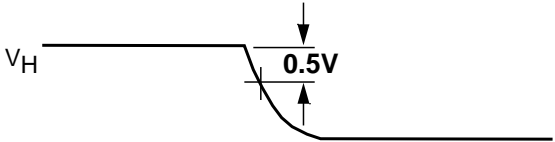
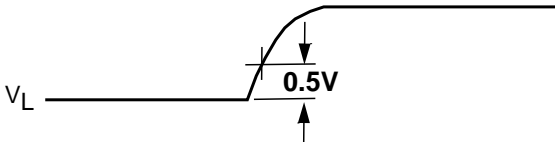
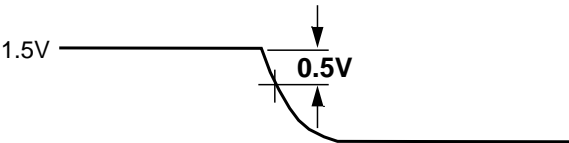
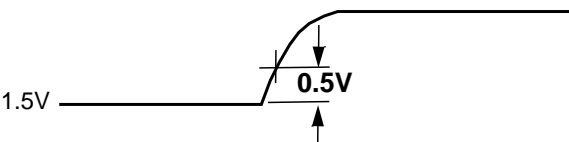
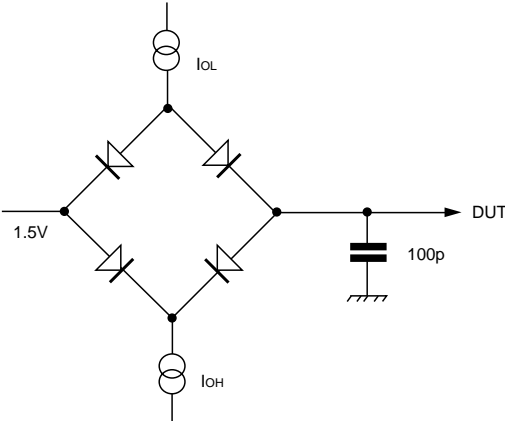
Supply voltage $V_{CC}$	-0.5V to 7.0V
Input voltage $V_{IN}$	-0.9V to $V_{CC} + 0.9V$
Output voltage $V_{OUT}$	-0.9V to $V_{CC} + 0.9V$
Clamp diode current per $I_k$ (see Note 2)	18mA
Static discharge voltage (HMB) $V_{STAT}$	500V
Storage temperature range $T_s$	-65°C to +150°C
Ambient temperature with power applied $T_{amb}$	
Military	-55°C to +125°C
Junction temperature	150°C
Package power dissipation $P_{TOT}$	1000mW

## THERMAL CHARACTERISTICS

Package Type	$\theta_{JC}$ °C/W
GC	12

## NOTES

- Exceeding these ratings may cause permanent damage. Functional operation under these conditions is not implied.
- Maximum dissipation or 1 second should not be exceeded, only one output to be tested at any one time.
- Exposure to absolute maximum ratings for extended periods may affect device reliability.

Test	Waveform - measurement level
Delay from ouput high to output high impedance	
Delay from ouput low to output high impedance	
Delay from ouput high impedance to Output low	
Delay from ouput high impedance to Output high	
<div>NOTES</div> <div><div>1. <math>V_H</math> - Voltage reached when output driven high</div><div>2. <math>V_L</math> - Voltage reached when output driven low</div></div> <div></div>	

# PDSP16318 MC

## ELECTRICAL CHARACTERISTICS

Test conditions (unless otherwise stated):

$T_{amb}$  (Military) = -55°C to +125°C,  $V_{CC} = 5.0V \pm 10\%$ , GND = 0V

## STATIC CHARACTERISTICS

Characteristic	Symbol	Value			Units	Sub group	Conditions
		Min.	Typ.	Max.			
* Output high voltage	$V_{OH}$	2.4		-	V	1, 2, 3	$I_{OH} = 3.2mA$ $I_{OL} = -3.2mA$
* Output low voltage	$V_{OL}$	-		0.4	V	1, 2, 3	
* Input high voltage	$V_{IH}$	2.0		-	V	1, 2, 3	
* Input low voltage	$V_{IL}$	-		0.8	V	1, 2, 3	
	$V_{IH}$	Vdd - 1		-	V	1, 2, 3	CLK, $\overline{CEA}$ , $\overline{CEB}$ , $\overline{OEC}$ , $\overline{OED}$ CLK, $\overline{CEA}$ , $\overline{CEB}$ , $\overline{OEC}$ , $\overline{OED}$
	$V_{IL}$	-		0.5	V	1, 2, 3	
* Input leakage current	$I_{IL}$	-10		+10	$\mu A$	1, 2, 3	
* Output leakage current	$I_{oz}$	-50	-	+50	$\mu A$	1, 2, 3	
† Output SC current	$I_{OS}$	20	-	200	mA		$GND \leq V_{IN} \leq V_{CC}$ $V_{CC} = \text{Max}$
† Input capacitance	$C_{IN}$	-	9	-	pF		

## SWITCHING CHARACTERISTICS

Characteristic	Value Military		Units	Sub group	Conditions
	PDSP16318				
	Min.	Max.			
* Clock period	100	-	ns	9, 10, 11	2 x LSTTL + 20pF 2 x LSTTL + 20pF 2 x LSTTL + 20pF 2 x LSTTL + 20pF V <sub>CC</sub> = max, TTL input levels Outputs unloaded, f <sub>CLK</sub> = max
† Clock High Time	20	-	ns		
† Clock Low Time	20	-	ns		
† A15:0, B15:0 setup to clock rising edge	8	-	ns		
† A15:0, B15:0 hold after clock rising edge	2	-	ns		
† MS, S2:0, ASI setup to clock rising edge	10	-	ns		
† DEL, ASR, $\overline{\text{CLR}}$ setup to clock rising edge	8	-	ns		
† DEL, ASR, $\overline{\text{CLR}}$ , MS, S2:0, ASI hold after clock rising edge	2	-	ns		
† $\overline{\text{CEA}}$ , $\overline{\text{CEB}}$ setup to clock falling edge	2	-	ns		
† $\overline{\text{CEA}}$ , $\overline{\text{CEB}}$ hold after clock falling edge	8	-	ns		
† Clock rising edge to OVR, C15:0, D15:0	5	40	ns		
† $\overline{\text{OEC}}/\overline{\text{OED}}$ low to C15:0/D15:0 high data valid	-	40	ns		
† $\overline{\text{OEC}}/\overline{\text{OED}}$ low to C15:0/D15:0 low data valid	-	40	ns		
† $\overline{\text{OEC}}/\overline{\text{OED}}$ high to C15:0/D15:0 high impedance	-	40	ns		
† V <sub>CC</sub> current	-	70	mA		
† V <sub>CC</sub> current	-	30	mA	V <sub>CC</sub> = max, CMOS input levels Outputs unloaded, f <sub>CLK</sub> = max	

All parameters marked \* are tested during production.

All parameters marked † are guaranteed by design and characterisation.

## NOTES

1. LSTTL is equivalent to  $I_{OH} = 20$  microamps,  $I_{OL} = -0.4mA$
2. Current is defined as negative into the device
3. CMOS input levels are defined as:  
 $V_{IL} = 0.5V$   
 $V_{IH} = V_{DD} - 0.5V$

# PDSP16318 MC

Part No: PDSP16318 AC Complex Accumulator  
Package Type: GC100

Pin No.	Con.	Pin No.	Con.	Pin No.	Con.	Pin No.	Con.
1	N/C	26	0V	51	0V	76	N/C
2	N/C	27	N/C	52	N/C	77	N/C
3	N/C	28	N/C	53	N/C	78	N/C
4	N/C	29	N/C	54	N/C	79	N/C
5	N/C	30	N/C	55	N/C	80	N/C
6	N/C	31	0V	56	0V	81	N/C
7	N/C	32	0V	57	0V	82	N/C
8	N/C	33	0V	58	0V	83	N/C
9	N/C	34	0V	59	V1	84	N/C
10	N/C	35	0V	60	V1	85	V1
11	N/C	36	0V	61	V1	86	0V
12	N/C	37	0V	62	V1	87	N/C
13	N/C	38	V1	63	V1	88	N/C
14	V1	39	V1	64	V1	89	N/C
15	V1	40	V1	65	V1	90	N/C
16	0V	41	V1	66	V1	91	N/C
17	0V	42	V1	67	V1	92	N/C
18	V1	43	V1	68	V1	93	N/C
19	V1	44	V1	69	N/C	94	N/C
20	0V	45	V1	70	N/C	95	N/C
21	0V	46	V1	71	N/C	96	V1
22	V1	47	0V	72	N/C	97	0V
23	0V	48	0V	73	N/C	98	N/C
24	V1	49	0V	74	N/C	99	N/C
25	V1	50	0V	75	N/C	100	N/C

N/C = not connected - leave open circuit  
All GND and VDD pins must be used

*Fig.4 Life Test/Burn-in connections*  
*NOTE: PDA is 5% and based on groups 1 and 7*



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